

# Comparing all wavelengths

#characteristic\_lenghts

#ell

#ellDW

#ellCC

We can measure three characteristic wavelengths in the system:

$\ell$

$$\langle q^2 \rangle \equiv \frac{\int q^2 |u_q|^2 dq}{\int |u_q|^2 dq}$$
$$\ell \equiv \frac{2\pi}{\sqrt{\langle q^2 \rangle}}$$

We know from [Linear regime](#) that, during the linear regime

$$\ell \sim t^{\frac{1}{2}}$$

Then, in appendix G of the [Master Report.pdf](#) we show that, asymptotically this wavelength is related to  $\ell_{DW}$  that asymptotically shows the coarsening exponent  $\frac{1}{2}$ :  $\ell_{DW} \sim t^{\frac{1}{2}}$  so

$$\ell \sim t^{\frac{1}{4}}$$

$\ell_{DW}$

$$\ell_{DW} = \frac{L^2}{\int |\nabla u|^2 dx dy} * W$$

Where  $W$  is the width of the interface, defined as the integral of the derivative of the field  $u(x, y)$  along a direction perpendicular to the interface. We estimate this integral by considering the stationary state with  $C = \bar{C}$ :

$$u_k(\xi) = \sqrt{C} \tanh\left(\sqrt{\frac{C}{2}} \xi\right)$$
$$W = \int_{-\infty}^{\infty} (\partial_{\xi} u_k(\xi))^2 d\xi = \frac{2}{3} \sqrt{2} C^{\frac{3}{2}}$$

(the last integral is calculated in Appendix G of the [Master Report.pdf](#)).

As the gradient is peaked in the regions close to the interfaces,  $\ell_{DW}$  should estimate the ratio between the size of the system  $L^2$  and the (total) length of the interfaces  $\mathcal{L}$ .

$\ell_{CC}$

We estimate the (total) length of the interfaces  $\mathcal{L}$  by using the Cauchy-Crofton theorem, using 4 families of parallel lines: horizontal, vertical,  $\pi/4$ ,  $3\pi/4$ . Then we calculate

$$\ell_{CC} = \frac{L^2}{\mathcal{L}}$$

The Cauchy-Croft formula is

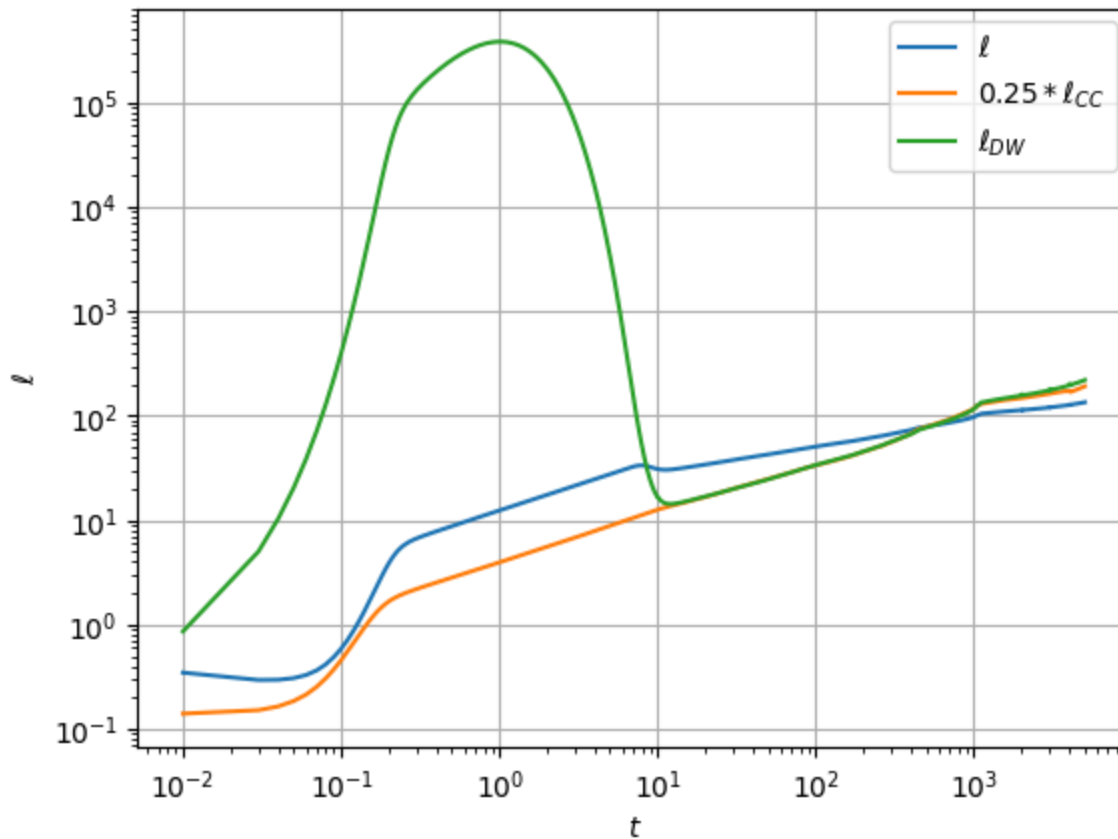
$$\mathcal{L} \simeq \frac{1}{2} * n * dx * (\pi/4)$$

([do Carmo, Manfredo. Differential geometry of curves and surfaces.pdf](#) P. 48)

- $n$  is the number of times the interface crosses the parallel lines
- $dx$  is the spacing between the lines

## Comparison (in the same canvas)

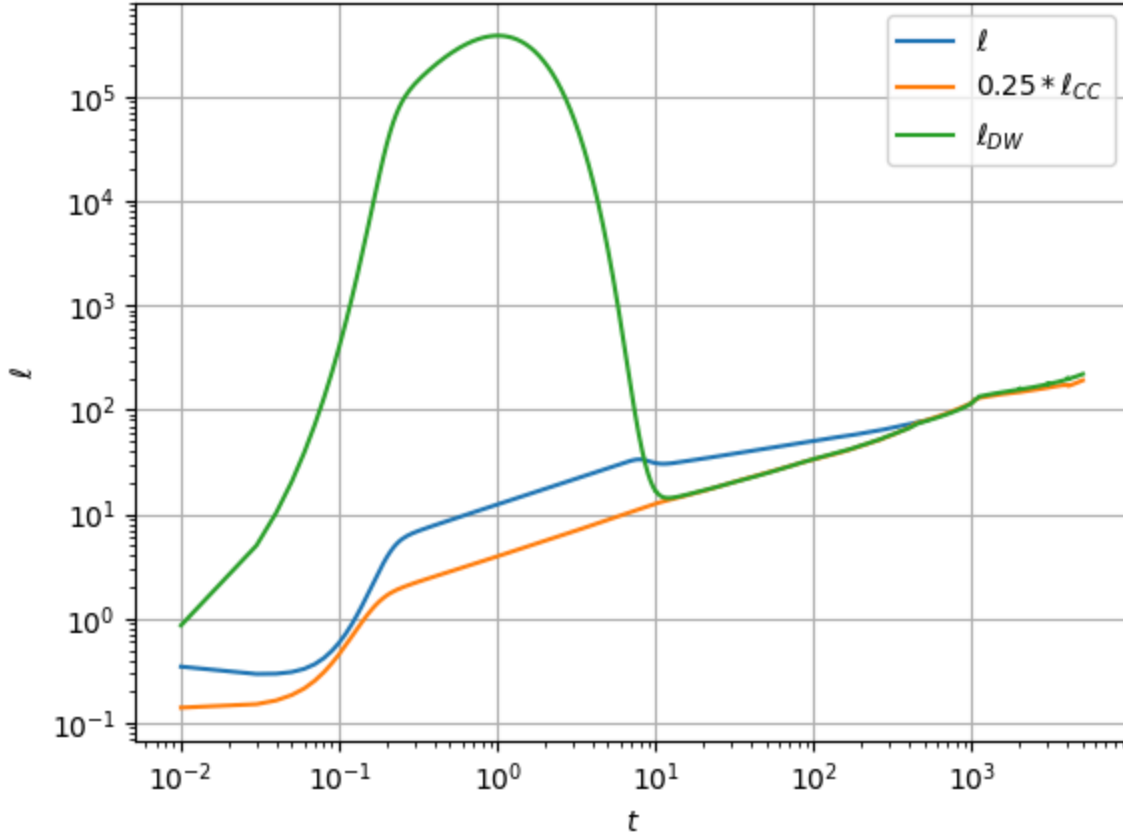
Lattice points = 4096  $dx = 0.1$   
 $dt = 0.01$  until  $t=20$ ; Then  $dt = 0.1$   
 $C = 1$  const.



In the following plot, the thickness of the interface is estimated as the one of the stationary state associated with constant  $C = \bar{C}$ .

Lattice points [4096 x 4096]; dx = 0.1

$C = 1 + A \sin(2\pi t/T); A = 1/4; T = 1/10$



**NOTICE:** We expect that, asymptotically, when domains are formed

$$\ell_{DW} \simeq \ell_{CC} \simeq \frac{L^2}{\mathcal{L}}$$

But there is a factor 1/4 of difference.

The next paragraph suggests that  $\ell_{DW}$  well estimates the (total) length of the interfaces. So **probably there is a problem with estimating  $\ell_{CC}$ .**

## Comparison (Asymptotically)

Asymptotically, precisely when  $\ell_{DW}$  well estimates the ratio  $L^2/\mathcal{L}$ :

$$\ell^{-2} \simeq (2\pi)^{-2} D^{-1} I_1 (C\ell_{DW} - I_2)^{-1}$$

Then, at sufficiently large times:  $\ell_{DW}$  grows, so  $(C\ell_{DW} - I_2) \simeq C\ell_{DW}$  that means

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$$\ell^{-2} = (2\pi)^{-2} (CD\ell_{DW})^{-1} I_1$$

Calculating the logarithm:

$$\log \ell = \frac{1}{2} \log \ell_{DW} + \text{const.}$$

$$const. = \log 2\pi + \frac{1}{2}\log(CD) - \frac{1}{2}\log I_1$$

Lattice points = 4096  $dx = 0.1$   
 $dt = 0.01$  until  $t=20$ ; Then  $dt = 0.1$   
 $C = 1$  const.

